

XC9536XV High-performance CPLD

DS053 (v3.0) June 25, 2007

Note: This product is being discontinued. You cannot order parts after May 14, 2008. Xilinx recommends replacing XC9536XV devices with equivalent XC9536XL devices in all designs as soon as possible. Recommended replacements are pin compatible, however require a V_{CC} change to 3.3V, and a recompile of the design file. In addition, there is no 1.8V I/O support. See <u>XCN07010</u> for details regarding this discontinuation, including device replacement recommendations for the XC9536XV CPLD.

Features

- 36 macrocells with 800 usable gates
- Available in small footprint package
 - 44-pin VQFP (34 user I/O pins)
- Optimized for high-performance 2.5V systems
 - Low power operation
 - Multi-voltage operation
- Advanced system features
 - In-system programmable
 - Superior pin-locking and routability with Fast CONNECT™ II switch matrix
 - Extra wide 54-input Function Blocks
 - Up to 90 product-terms per macrocell with individual product-term allocation
 - Local clock inversion with three global and one product-term clocks
 - Individual output enable per output pin
 - Input hysteresis on all user and boundary-scan pin inputs
 - Bus-hold circuitry on all user pin inputs
 - Full IEEE Standard 1149.1 boundary-scan (JTAG)
- Fast concurrent programming
- Slew rate control on individual outputs
- Enhanced data security features
- Excellent quality and reliability
 - 20 year data retention
 - ESD protection exceeding 2,000V
- Pin-compatible with 3.3V-core XC9536XL device in the 44-pin VQFP package

Description

The XC9536XV is a 2.5V CPLD targeted for high-performance, low-voltage applications in leading-edge communications and computing systems. It is comprised of two 54V18 Function Blocks, providing 800 usable gates with propagation delays of 5 ns. See Figure 2 for architecture overview.

Product Specification

Power Estimation

Power dissipation in CPLDs can vary substantially depending on the system frequency, design application and output loading. To help reduce power dissipation, each macrocell in a XC9500XV device may be configured for low-power mode (from the default high-performance mode). In addition, unused product-terms and macrocells are automatically deactivated by the software to further conserve power. For a general estimate of I_{CC} , the following equation may be used:

 $P_{TOTAL} = P_{INT} + P_{IO} = I_{CCINT} \times V_{CCINT} + P_{IO}$

Separating internal and I/O power here is convenient because XC9500XV CPLDs also separate the corresponding power pins. P_{IO} is a strong function of the load capacitance driven, so it is handled by I = CVf. I_{CCINT} is another situation that reflects the actual design considered and the internal switching speeds. An estimation expression for I_{CCINT} (taken from simulation) is:

$$\begin{split} I_{CCINT}(mA) &= MC_{HS}(0.122 \text{ X PT}_{HS} + 0.238) + MC_{LP}(0.042 \text{ x} \\ PT_{LP} + 0.171) + 0.04(MC_{HS} + MC_{LP}) \text{ x } f_{MAX} \text{ x } MC_{TOG} \\ \text{where:} \end{split}$$

MC_{HS} = # macrocells used in high speed mode

MC_{LP} = #macrocells used in low power mode

PT_{HS} = average p-terms used per high speed macrocell

 PT_{IP} = average p-terms used over low power macrocell

 f_{MAX} = max clocking frequency in the device

 MC_{TOG} = % macrocells toggling on each clock (12% is frequently a good estimate

This calculation was derived from laboratory measurements of an XC9500XV part filled with 16-bit counters and allowing a single output (the LSB) to be enabled. The actual I_{CC} value varies with the design application and should be verified during normal system operation. Figure 1 shows the above estimation in a graphical form. For a more detailed discussion of power consumption in this device, see Xilinx

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application note <u>XAPP361, "Planning for High Speed</u> <u>XC9500XV Designs."</u>

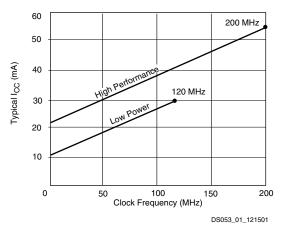
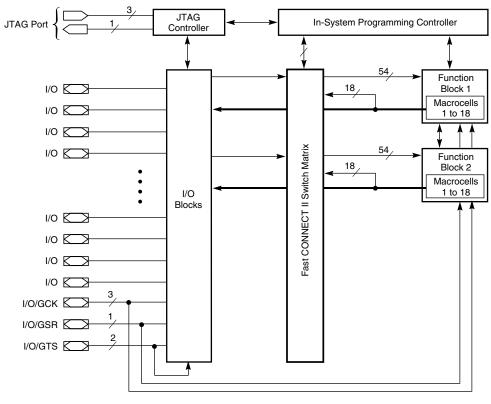


Figure 1: Typical I_{CC} vs. Frequency for XC9536XV



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Figure 2: **XC9536XV Architecture** Function block outputs (indicated by the bold line) drive the I/O Blocks directly.

Supported I/O Standards

Table 1: IOSTANDARD Options

IOSTANDARD	V _{CCIO}
LVTTL	3.3V
LVCMOS2	2.5V
X25TO18	1.8V

The XC9536XV CPLD features both LVCMOS and LVTTL I/O implementations. See Table 1 for I/O standard voltages.

The LVTTL I/O standard is a general purpose EIA/JEDEC standard for 3.3V applications that use an LVTTL input buffer and Push-Pull output buffer. The LVCMOS2 standard is used in 2.5V applications.

XC9500XV CPLDs are also 1.8V I/O compatible. The X25TO18 setting is provided for generating 1.8V compatible outputs from a CPLD normally operating in a 2.5V environment. The default I/O Standard for pads without IOSTAN-DARD attributes is LVTTL for XC9500XV devices.

Absolute Maximum Ratings

Symbol	Description	Value	Units
V _{CC}	Supply voltage relative to GND	-0.5 to 2.7	V
V _{CCIO}	Supply voltage for output drivers	-0.5 to 3.6	V
V _{IN}	Input voltage relative to GND ⁽¹⁾	-0.5 to 3.6	V
V _{TS}	Voltage applied to 3-state output ⁽¹⁾	-0.5 to 3.6	V
T _{STG}	Storage temperature (ambient)	-65 to +150	°C
TJ	Junction temperature	+150	°C

Notes:

 Maximum DC undershoot below GND must be limited to either 0.5V or 10 mA, whichever is easier to achieve. During transitions, the device pins may undershoot to -2.0V or overshoot to +3.6V, provided this over- or undershoot lasts less than 10 ns and with the forcing current being limited to 200 mA.

2. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

3. For solder specifications, see Xilinx Packaging.

Recommended Operation Conditions

Symbol	Para	meter	Min	Max	Units
V _{CCINT}	Supply voltage for internal logic	Commercial $T_A = 0^{\circ}C$ to +70°C	2.37	2.62	V
	and input buffers	Industrial $T_A = -40^{\circ}C$ to +85°C	2.37	2.62	
V _{CCIO}	Supply voltage for output drivers f	Supply voltage for output drivers for 3.3V operation			V
	Supply voltage for output drivers for 2.5V operation		2.37	2.62	V
	Supply voltage for output drivers f	1.71	1.89	V	
V _{IL}	Low-level input voltage		0	0.8	V
V _{IH}	High-level input voltage	1.7	3.6	V	
V _O	Output voltage	0	V _{CCIO}	V	

Quality and Reliability Characteristics

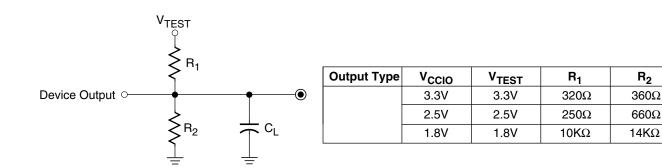
Symbol	Parameter	Min	Max	Units
T _{DR}	Data Retention	20	-	Years
N _{PE}	Program/Erase Cycles (Endurance)	1,000	-	Cycles
V _{ESD}	Electrostatic Discharge (ESD)	2,000	-	Volts

DC Characteristics (Over Recommended Operating Conditions)

Symbol	Parameter	Test Conditions	Min	Max	Units
V _{OH}	Output high voltage for 3.3V outputs	I _{OH} = -4.0 mA	2.4	-	V
	Output high voltage for 2.5V outputs	I _{OH} = -1.0 mA	2.0	-	V
	Output high voltage for 1.8V outputs	I _{OH} = −100 μA	90% V _{CCIO}	-	V
V _{OL}	Output low voltage for 3.3V outputs	I _{OL} = 8.0 mA	-	0.4	V
	Output low voltage for 2.5V outputs	I _{OL} = 1.0 mA	-	0.4	V
	Output low voltage for 1.8V outputs	I _{OL} = 100 μA	-	0.4	V
I _{IL}	Input leakage current	V _{CC} = 2.62V V _{CCIO} = 3.6V V _{IN} = GND or 3.6V	-	±10	μΑ
I _{IH}	Input high-Z leakage current	V _{CC} = 2.62V V _{CCIO} = 3.6V V _{IN} = GND or 3.6V	-	±10	μA
		V_{CC} min < V_{IN} < 3.6V	-	±150	μΑ
C _{IN}	I/O capacitance	V _{IN} = GND f = 1.0 MHz	-	10	pF
I _{CC}	Operating Supply Current (low power mode, active)	$V_{I} = GND$, No load f = 1.0 MHz	7		mA

AC Characteristics

		XC95	36XV-5	XC95	Ι	
Symbol	Parameter	Min	Max	Min	Max	Units
T _{PD}	I/O to output valid	-	5.0	-	7.5	ns
Τ _{SU}	I/O setup time before GCK	3.5	-	4.8	-	ns
т _н	I/O hold time after GCK	0	-	0	-	ns
т _{со}	GCK to output valid	-	3.5	-	4.5	ns
f _{SYSTEM}	Multiple FB internal operating frequency	-	222.2	-	125.0	MHz
T _{PSU}	I/O setup time before p-term clock input	1.0	-	1.6	-	ns
T _{PH}	I/O hold time after p-term clock input	2.5	-	3.2	-	ns
T _{PCO}	P-term clock output valid	-	6.0	-	7.7	ns
T _{OE}	GTS to output valid	-	4.0	-	5.0	ns
T _{OD}	GTS to output disable	-	4.0	-	5.0	ns
T _{POE}	Product term OE to output enabled	-	7.0	-	9.5	ns
T _{POD}	Product term OE to output disabled	-	7.0	-	9.5	ns
T _{AO}	GSR to output valid	-	10.0	-	12.0	ns
T _{PAO}	P-term S/R to output valid	-	10.7	-	12.6	ns
T_{WLH}	GCK pulse width (High or Low)	2.2	-	4.0	-	ns
T _{PLH}	P-term clock pulse width (High or Low)	5.0	-	6.5	-	ns
T _{APRPW}	Asynchronous preset/reset pulse width (High or Low)	5.0	-	6.5	-	ns



DS051_03_0601000

 C_L

35 pF

35 pF

35 pF

Figure 3: AC Load Circuit

Internal Timing Parameters

		XC95	36XV-5	XC953		
Symbol	Parameter	Min	Max	Min	Max	Units
Buffer De	lays	•				•
T _{IN}	Input buffer delay	-	2.0	-	2.3	ns
Т _{GCK}	GCK buffer delay	-	1.2	-	1.5	ns
T _{GSR}	GSR buffer delay	-	2.0	-	3.1	ns
T _{GTS}	GTS buffer delay	-	4.0	-	5.0	ns
Τ _{ΟUT}	Output buffer delay	-	2.1	-	2.5	ns
T _{EN}	Output buffer enable/disable delay	-	0	-	0	ns
Product T	erm Control Delays					
Т _{РТСК}	Product term clock delay	-	1.7	-	2.4	ns
T _{PTSR}	Product term set/reset delay	-	0.7	-	1.4	ns
T _{PTTS}	Product term 3-state delay	-	5.0	-	7.2	ns
Internal R	egister and Combinatorial Delays	I		1		- I
T _{PDI}	Combinatorial logic propagation delay	-	0.2	-	1.3	ns
T _{SUI}	Register setup time	2.0	-	2.6	-	ns
Т _{НІ}	Register hold time	1.5	-	2.2	-	ns
T _{ECSU}	Register clock enable setup time	2.0	-	2.6	-	ns
T _{ECHO}	Register clock enable hold time	1.5	-	2.2	-	ns
Т _{СОІ}	Register clock to output valid time	-	0.2	-	0.5	ns
T _{AOI}	Register async. S/R to output delay	-	5.9	-	6.4	ns
T _{RAI}	Register async. S/R recover before clock	5.0		7.5		ns
T _{LOGI}	Internal logic delay	-	0.7	-	1.4	ns
T _{LOGILP}	Internal low power logic delay	-	5.7	-	6.4	ns
Feedback	Delays	I		1		- I
T _F	Fast CONNECT II feedback delay	-	1.6	-	3.5	ns
Time Add	ers		•	•		
T _{PTA}	Incremental product term allocator delay	-	0.7	-	0.8	ns
T _{PTA2}	Adjacent macrocell p-term allocator delay	-	0.3	-	0.3	ns
T _{SLEW}	Slew-rate limited delay	-	3.0	-	4.0	ns

XC9536XV I/O Pins

Function Block	Macrocell	VQ44	BScan Order	Function Block	Macrocell	VQ44	BScan Order
1	1	40	105	2	1	39	51
1	2	41	102	2	2	38	48
1	3	43(1)	99	2	3	36 ⁽¹⁾	45
1	4	42	96	2	4	37	42
1	5	44(1)	93	2	5	34 ⁽¹⁾	39
1	6	2	90	2	6	33 ⁽¹⁾	36
1	7	1(1)	87	2	7	32	33
1	8	3	84	2	8	31	30
1	9	5	81	2	9	30	27
1	10	6	78	2	10	29	24
1	11	7	75	2	11	28	21
1	12	8	72	2	12	27	18
1	13	12	69	2	13	23	15
1	14	13	66	2	14	22	12
1	15	14	63	2	15	21	9
1	16	16	60	2	16	20	6
1	17	18	57	2	17	19	3
1	18	-	54	2	18	-	0

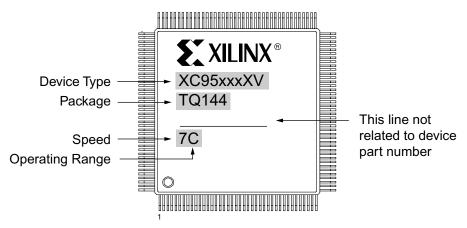
Notes:

1. Global control pin.

XC9536XV Global, JTAG and Power Pins

Pin Type	VQ44
I/O/GCK1	43
I/O/GCK2	44
I/O/GCK3	1
I/O/GTS1	36
I/O/GTS2	34
I/O/GSR	33
ТСК	11
TDI	9
TDO	24
TMS	10
V _{CCINT} 2.5V	15, 35
V _{CCIO} 1.8vV/2.5V/3.3V	26
GND	4, 17, 25
No Connects	-

Device Part Marking and Ordering Combination Information



Sample package with part marking.

Notes:

- 1. Due to the small size of chip scale packages, part marking on these packages does not follow the above sample and the complete part number cannot be included in the marking. Part marking on chip scale packages by line:
 - Line 1 = X (Xilinx logo), then truncated part number (no XC), i.e., 95xxxXV.
 - Line 2 = Not related to device part number.
 - Line 3 = Not related to device part number.
 - Line 4 = Package code, speed, operating temperature, three digits not related to device part number. Package code: C1 = CS48.

Device Ordering and Part Marking Number	Speed (pin-to-pin delay)	Pkg. Symbol	No. of Pins	Package Type	Operating Range ⁽¹⁾
XC9536XV-5VQ44C	5 ns	VQ44	44-pin	Quad Flat Pack (VQFP)	С
XC9536XV-7VQ44C	7.5 ns	VQ44	44-pin	Quad Flat Pack (VQFP)	С
XC9536XV-7VQ44I	7.5 ns	VQ44	44-pin	Quad Flat Pack (VQFP)	I

Notes:

1. C = Commercial: $T_A = 0^\circ$ to +70°C; I = Industrial: $T_A = -40^\circ$ to +85°C.

2. Some packages available in Pb-free option. See Xilinx Packaging for more information.

Revision History

Date	Revision No.	Description
02/01/00	1.1	Initial Xilinx release. Advance information specification.
01/29/01	2.0	Added -3 performance specification and VQ44 package. Deleted VQ64 package. Updated I_{CC} vs. Frequency Figure 1.
05/15/01	2.1	Updated I _{CC} formula, Recommended Operation Conditions, -3, -4, and -5 AC Characteristics and Internal Timing Parameters
08/27/01	2.2	Changed V _{CCIO} 3.3V from 3.13 to 3.0 (min), 3.46 to 3.60 (max); DC characteristics: I _{IL} - added "low" current, I _{IH} - changed to "Input leakage high current"; Internal Timing: -3 T _{CGK} from 0.3 to 0.8; -5 T _{AOI} from 6.5 to 5.9.
05/31/02	2.3	Updated I _{CC} equation on page 1. Removed -3 device. Changed to Preliminary. Added C4 and D4 as NCs in the CS48 package pinouts. Added second test condition and max measurement to I _{IH} DC Characteristics. Added Part Marking Information to Ordering Information. Removed -4 device.
05/27/03	2.4	Updated T _{SOL} from 260 to 220°C. Updated Device Part Marking.
08/21/03	2.5	Updated Package Device Marking Pin 1 orientation.
04/15/05	2.6	Added T _{APRPW} specification to AC Characteristics. Added IOSTANDARD information.
01/16/06	2.7	Removed PC44 and CS48 packages as per XCN05020.
06/25/07	3.0	Notice of discontinuance.